

SPIE Conference Optical Metrology 2011

Veranstaltung - SPIE Conference Optical Metrology 2011

Titel	SPIE Conference Optical Metrology 2011
Wann	So, 22. Mai 2011 - Do, 26. Mai 2011

Beschreibung

SPIE Conference Optical Metrology 2011

Co-located with Laser 2011 in Munich, Germany, this symposium provides an excellent opportunity to connect with engineers, researchers, and developers from Europe and beyond.

SPIE Optical Metrology is the premier conference in Europe that brings together scientists, engineers, researchers, and applications or product developers engaged in optical metrology, optical measurement systems, and optics for arts, architecture, and archaeology.

Please [look here for more information](#).

Lokalität - Neue Messe München

Standort	Neue Messe München
Straße	Am Messesee
Postleitzahl	81829
Ortsname	München
Bundesland	Bayern
Land	DE
Webseite	http://www.messe-muenchen.de